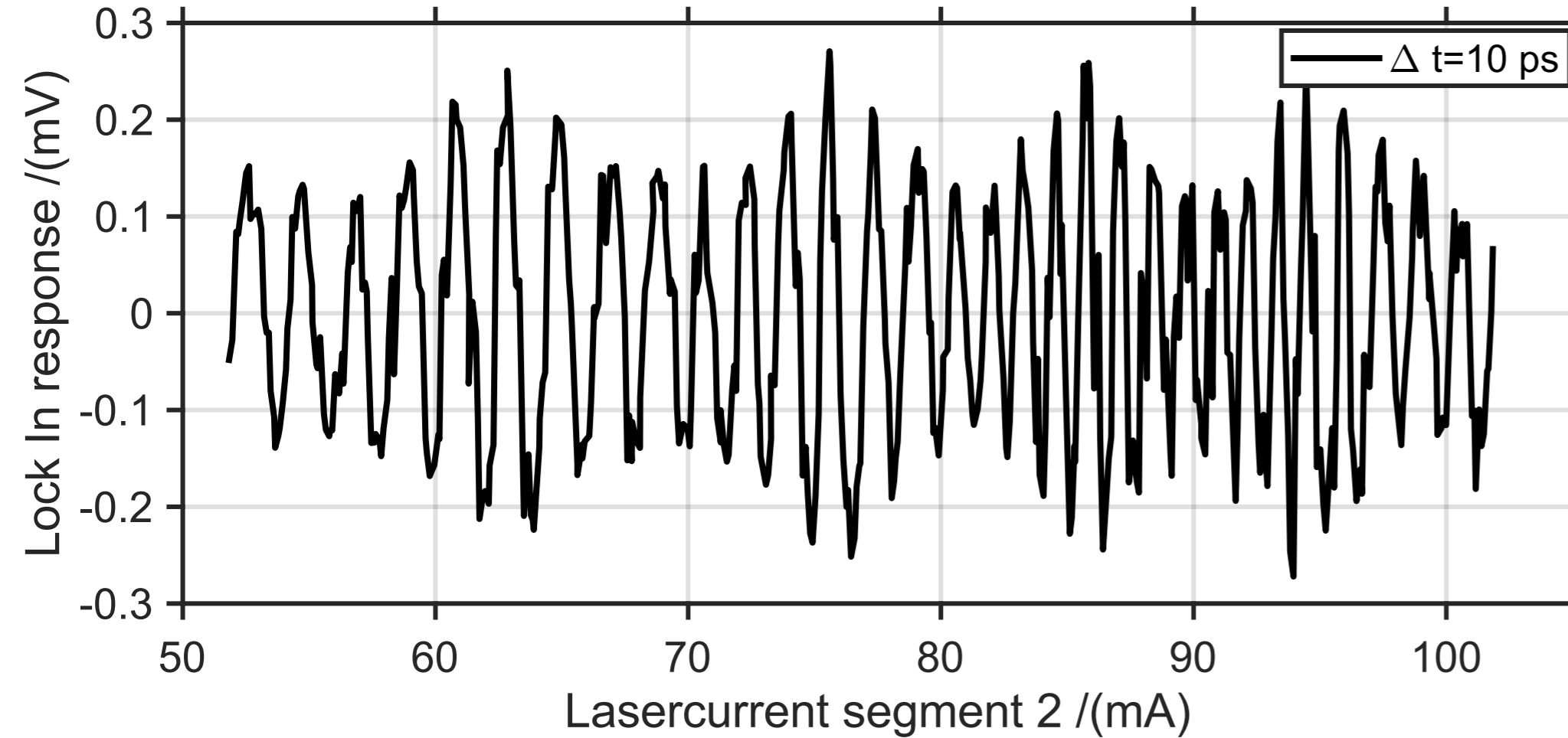


(a) FD scan of wafer



(b) fit of transmission function

